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U.S. PATENT DOCUMENTS										
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Xu	A	6,054,730	04/2000	Noguchi		257	306			
XV	· AB	6,466,489	10/2002	leong et al.		365	189.09	_		
XX	AC	6,579,751	06/2003	Tran		438	194			
XIL	AD	6,200,863	03/2001	Xiang et al.		438	286			
ALL	Æ	6,238,967	05/2001	Shiho et al.		438	244			
Sel	AF	6,620,679	09/2003	Tzeng et al.	•	438	250	·		
AL	AG.	6,008,080	12/1999	Chuang et al.		438	200			
The	АН	5,834,851	11/1998	Ikeda et al.		257	903	903		
XIL	A	5,371,026	12/1994	Hayden et al.		437	41			
X	۵.	2003/0205745	11/2003	Nam		257	296			
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1 /m	AM			Cell Transistor with Asy	mmetric Source a	nd Drain	Junction Pro	ofiles Impro	oving	
				es" IEEE, 2002, pp. 176-1		· · · · · · · · · · · · · · · · · · ·		•		
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If Appropriate Document Number 6,580,149 B2 06/17/03 Tean et al. 257 549 597 6,423,620 B2 07/23/02 Pan et al. 438 AC AB АF AG ΛH ΑJ A) ٨K ۸l. FOREIGN PATENT DOCUMENTS MM ٨N AP OTHER REFERENCES (including Author, Title, Date. Pertinent Pages, Etc.) ΑQ AR **EXAMINER** DATE CONSIDERED *EXAMINER: Initial if reference considered, whether or not considered. Include copy of this form with next communications citation is in conformance with MPEP 600; Draw line through citation it not in conformance and not by applicant.

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XD.	AA	4,61	12,629	09/16/86	HARARI		365	185		
XX	AB	4,78	35,342	11/15/88	YAMANARA ET AL.		357	51		
SAL	AC	5,78	36,249	07/28/98	DENNISON		438	241		
WILL)	AD	6,07	16,924	06/13/00	DENNISON ET AL.		438	386		
XIL	AE	5,27	72,367	12/21/93	DENNISON ET AL.		257	306		
XII	AF	6,00	14,854	12/21/99	DENNISON ET AL.		438	306		
XIL	AG	5.68	33.927	11/04/97	DENNISON ET AL		437	57	1	
NAL	АН	6,12	×4,616	09/26/00	DENNSION ET AL.		257	369		
THE	Al	5,74	7,855	05/05/98	DENNISON ET AL.		257	369		
XIL	, A3	5,53	4,449	07/09/96	DENNISON ET AL	·	437	34		
No	AK	5,70	16,806	07/07/98	DENNISON ET AL.		438	199		
XIL	AL	5,77	3,863	06/60/98	BURR ST AL.		257	344		
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U.S. PATENT DOCUMENTS										
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RD	AA	5,661,054	8/26/1997	KAUFFMAN ET AL.	-	438	257			
XX	¥В	5,736,444	4/07/1998	KAUFFMAN ET AL.		438	257			
XIL	۸C	6,337,250 B2	1/08/2002	FURUHATA		438	301			
All	AD	6,312,997 B1	11/6/2001	TRAN		438	303	<u> </u>		
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